

650V, 280mΩ, 14.1 A Super Junction Power MOSFET

Ordering Information

Part Number	Package Option
D3S280N65B-U	TO-220
D3S280N65E-T	TO-263
D3S280N65F-U	TO-220 FullPak (FP)

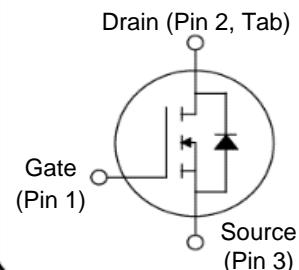


Description

+FET™ is an advanced Super Junction Power MOSFET offering excellent efficiency through low R_{DS(ON)} and low gate charge.

+FET™ is a rugged device with precision charge balance implementation designed for demanding uses such as enterprise power computing power supplies, motor control, lighting and other challenging power conversion applications.

Device Schematic



Features

- LOW R_{DS(ON)}
- FAST SWITCHING
- HIGH E_{AS}
- REL TEST SPEC: JESD-22
- LOW OUTPUT CAPACITANCE

Benefits

- LOW CONDUCTION LOSSES
- HIGH EFFICIENCY
- EXCELLENT AVALANCHE PERFORMANCE

Table 1 Key Performance Parameters

Parameters	Value	Unit
V _{DS} @ T _J max	710	V
RDS(on),max	<280	mΩ
Q _g ,typ	22	nC
I _D @ 25C	14	A
C _{oss}	41	pf

Applications

- POWER FACTOR CORRECTION
- SERVER POWER SUPPLIES
- TELECOM POWER SUPPLIES
- INVERTERS
- MOTOR CONTROL

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@ $T_J = 25^\circ\text{C}$, unless otherwise specified

Table 2 Maximum ratings

Parameter	Symbol	Values				Unit	Note/Test Condition		
		Min.	Typ.	Max.					
				220, 263 &247	220FP				
Continuous drain current(1)	I_D			14.1	7.8	A	$T_C = 25^\circ\text{C}$		
				8.9	4.9		$T_C = 100^\circ\text{C}$		
Pulsed drain current(2)	$I_{D,\text{pulse}}$			56.3	31.0	A	$T_C = 25^\circ\text{C}$		
Avalanche energy, single pulse	E_{AS}			260	260	mJ	$I_D=2.4\text{A}, V_{DD}=50\text{V}$		
Avalanche energy, repetitive	E_{AR}			0.65	0.65	mJ	$I_D=2.4\text{A}, V_{DD}=50\text{V}$		
Avalanche current, repetitive	I_{AR}			2.4	2.4	A			
MOSFET dv/dt ruggedness	dv/dt			50	50	V/ns	$V_{DS}=\dots480\text{V}$		
Gate source voltage	V_{GS}	-30		30	30	V	static		
		-30		30	30		AC ($f > 1\text{Hz}$)		
Power dissipation for TO-220	P_{tot}			147	45	W	$T_C = 25^\circ\text{C}$		
Operating and storage temperature	T_j, T_{stg}	-55		150	150	°C			
Mounting torque				60		Ncm	M3 and M3.5 screws		
					50		M3 screws		
Continuous diode forward current	I_S			14.1	7.8	A	$T_C = 25^\circ\text{C}$		
Diode pulsed current	$I_{S,\text{pulse}}$			56.3	31.0	A	$T_C = 25^\circ\text{C}$		
Reverse diode dv/dt(3)	dv/dt			15	15	V/ns	$V_{DS}=\dots480\text{V}, I_{SD} < I_D$ $T_J = 25^\circ\text{C}$		
Maximum diode commutation speed	dif/dt			500	500	A/us			

Table 3 Thermal characteristics

Parameter	Symbol	Values				Unit	Note/Test Condition		
		Min.	Typ.	Max.					
				220, 263 &247	220FP				
Thermal resistance, Junction-case	R_{thJC}			1.0	3.1	°C/W			
Thermal resistance, Junction-ambient	R_{thJA}			52	55	°C/W	Leaded		
Soldering temperature, wavesoldering only allowed at leads	T_{sold}			260	260	°C	1.6mm from case for 10s		

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note/Test Condition
		Min.	Typ.	Max.		
Drain to source breakdown voltage	$V_{(BR)DSS}$	650			V	$V_{GS}=0V, I_D=1mA$
Gate threshold voltage	$V_{GS(TH)}$	2.3	3.2	4.5	V	$V_{DS}=V_{GS}, I_D=71.7\mu A$
Zero gate voltage drain current	I_{DSS}			1	uA	$V_{DS}=650V, V_{GS}=0V, T_J = 25^\circ C$
				40		$V_{DS}=650V, V_{GS}=0V, T_J = 150^\circ C$
Gate to source leakage current	I_{GSS}			100	nA	$V_{GS}=\pm 20V, V_{DS}=0V$
Drain-source on-state resistance	$R_{DS(On)}$		267	280	mΩ	$V_{GS}=10V, I_D=7.1A, T_J = 25^\circ C$
			630		mΩ	$V_{GS}=10V, I_D=7.1A, T_J = 150^\circ C$
Gate resistance	R_G		1.0		Ω	Scaf-F

Table 5 Dynamic characteristics

Parameter	Symbol	Values			Unit	Note/Test Condition
		Min.	Typ.	Max.		
Input capacitance	C_{iss}		800		pF	$V_{GS}=0V, V_{DS}=100V, f=1MHz$
Output capacitance	C_{oss}		39.7		pF	
Reverse transfer capacitance	C_{rss}		7.5		pF	
Effective output capacitance, energy related 1	$C_{o(er)}$		69		pF	
Effective output capacitance, time related 2	$C_{o(tr)}$		147		pF	
Turn on delay time	$t_{d(on)}$		7		ns	
Rising time	t_r		21		ns	
Turn off delay time	$t_{d(off)}$		21		ns	
Fall time	t_f		23		ns	

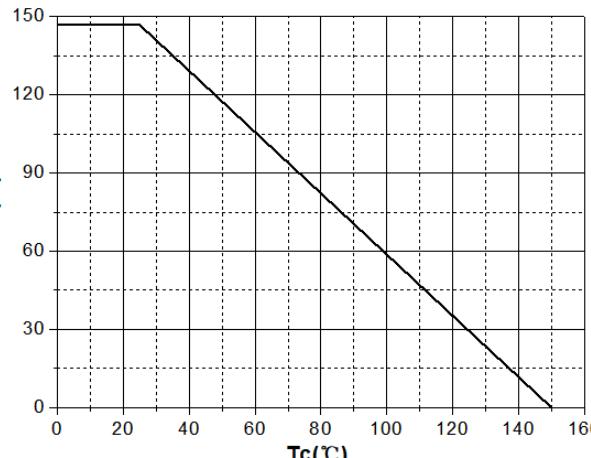
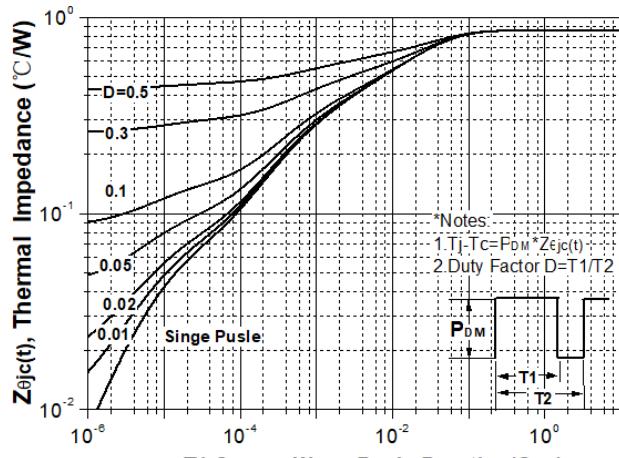
Table 6 Gate charge characteristics

Parameter	Symbol	Values			Unit	Note/Test Condition
		Min.	Typ.	Max.		
Total gate charge	Q_g		22		nC	$V_{DD}=480V, V_{GS}=0 \text{ to } 10V$ $I_D=7.1A$
Gate-source charge	Q_{gs}		6.2		nC	
Gate-drain charge	Q_{gd}		9.5		nC	
Gate plateau voltage	$V_{plateau}$		5.0		V	

Table 7 Reverse diode characteristics

Parameter	Symbol	Values			Unit	Note/Test Condition
		Min.	Typ.	Max.		
Diode forward voltage	V_{SD}		0.85	0.96	V	$I_F=14.1A, V_{GS}=0V, T_J = 25^\circ C$
Reverse recovery time	t_{rr}		266		ns	
Reverse recovery charge	Q_{rr}		2.8		uC	
Peak reverse recovery current	I_{rrm}		20		A	

Table 8 Thermal Performance

Power dissipation (TO220, TO263 & TO247)	Max. transient thermal impedance (TO220, TO263 & TO247)
	 <p>$P_{tot}=f(T_c)$</p>
	$Z_{thJC}=f(t_p); \text{parameter: } D=t_p/T$

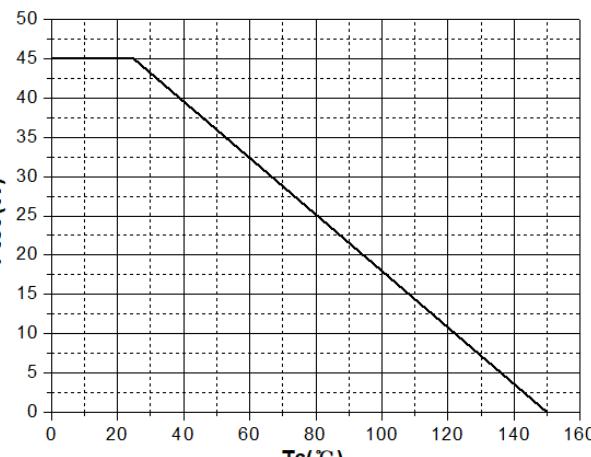
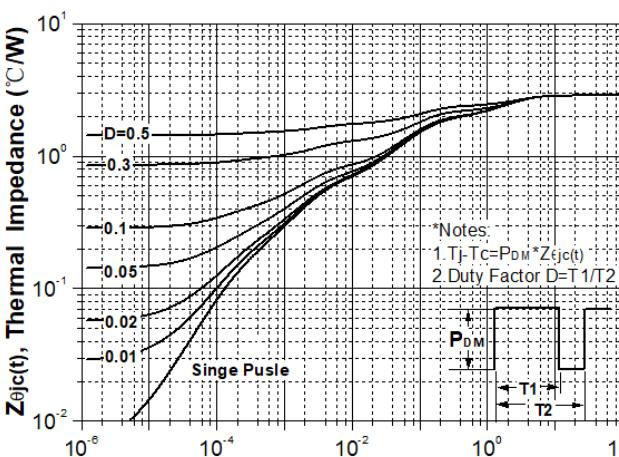
Power dissipation (TO220F)	Max.transient thermal impedance (TO220F)
	 <p>$P_{tot}=f(T_c)$</p>
	$Z_{thJC}=f(t_p); \text{parameter: } D=t_p/T$

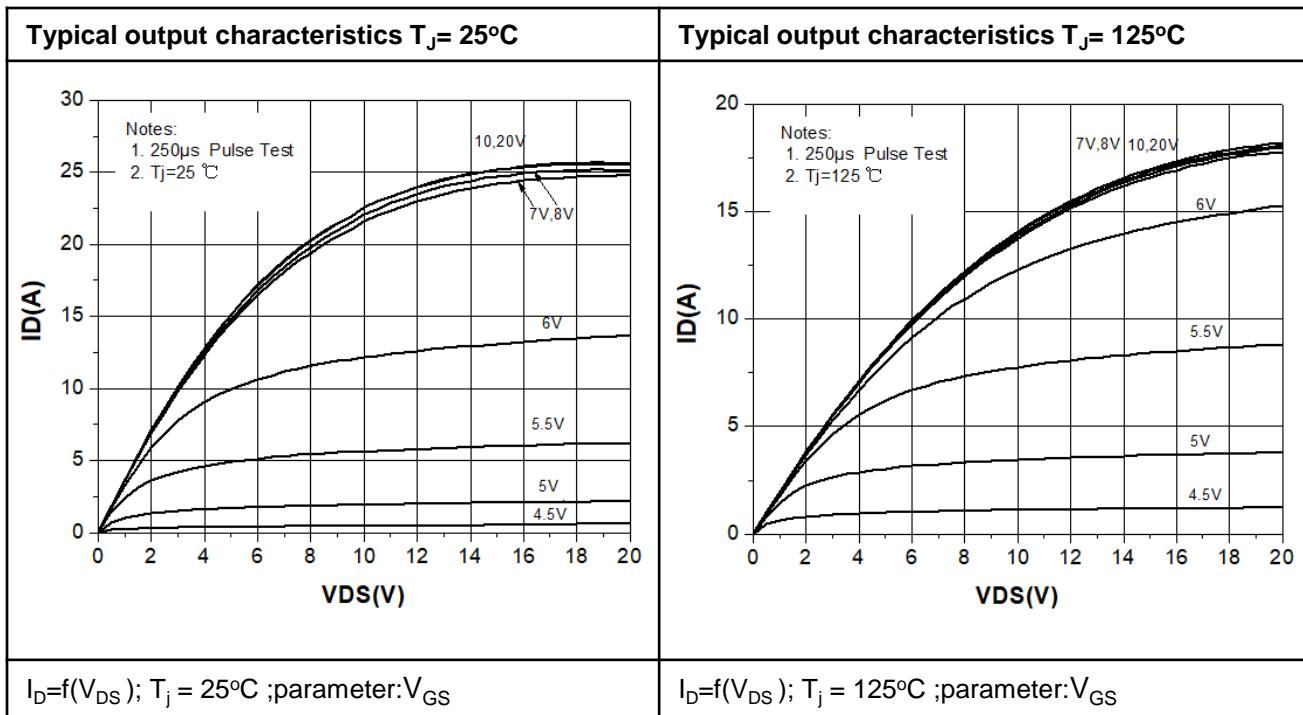
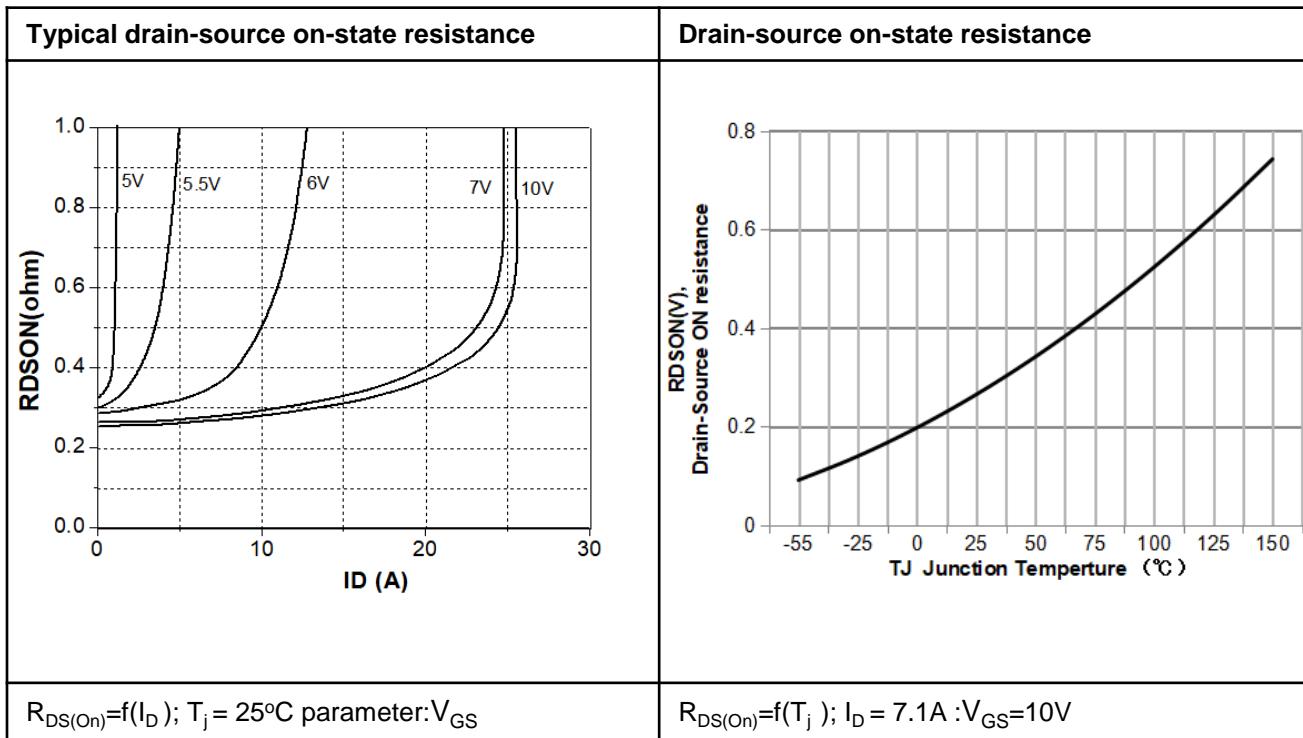
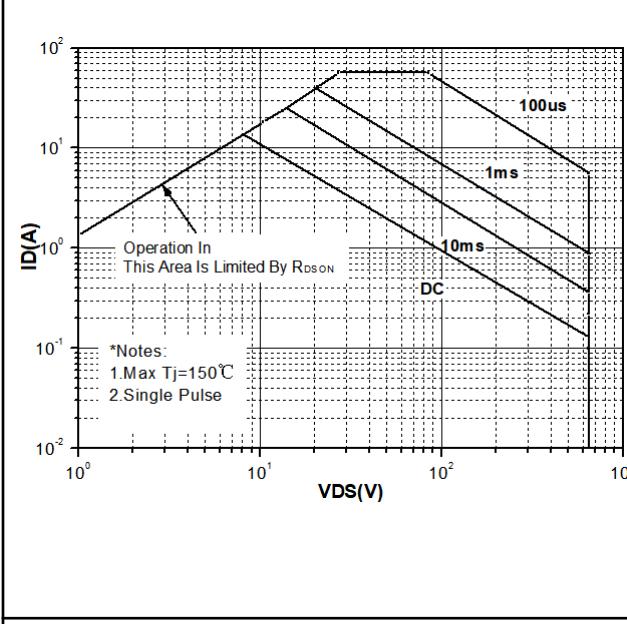
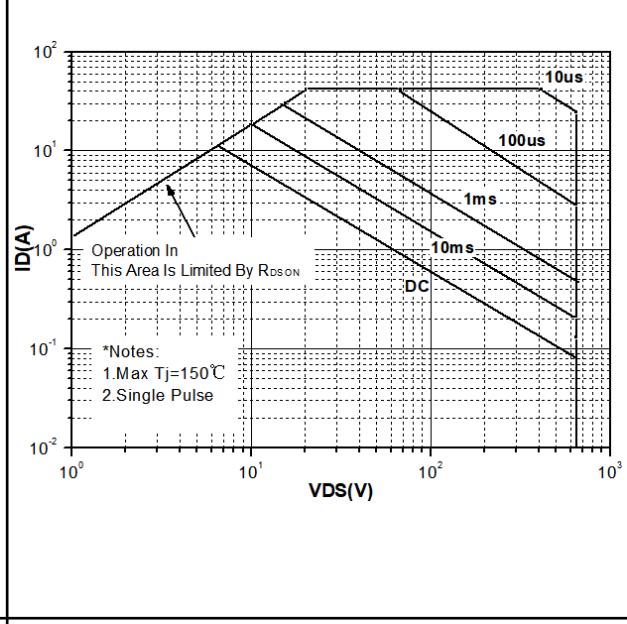
Table 9 Output Characteristics

Table 10 Drain Source Resistance


Table 11 Safe Operating Area

Safe operating area $T_C = 25^\circ\text{C}$ (TO220, TO263 & TO247)	Safe operating area $T_C = 80^\circ\text{C}$ (TO220, TO263 & TO247)
 <p>$I_D = f(V_{DS})$; $T_C = 25^\circ\text{C}$; $D=0$; parameter: t_P</p>	 <p>$I_D = f(V_{DS})$; $T_C = 80^\circ\text{C}$; $D=0$; parameter: t_P</p>

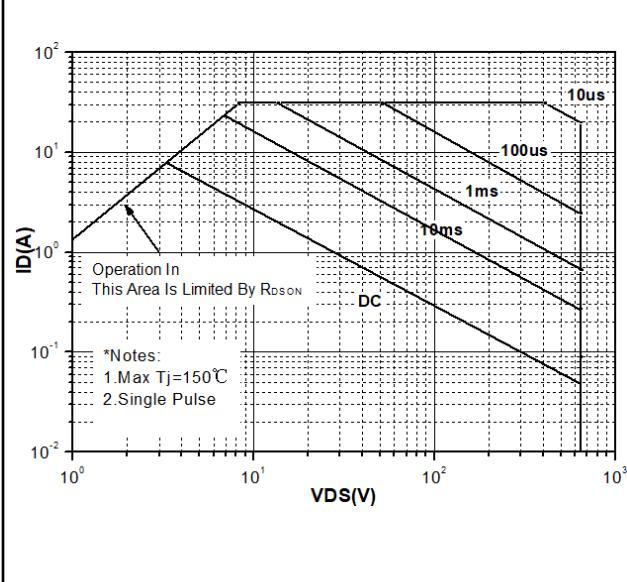
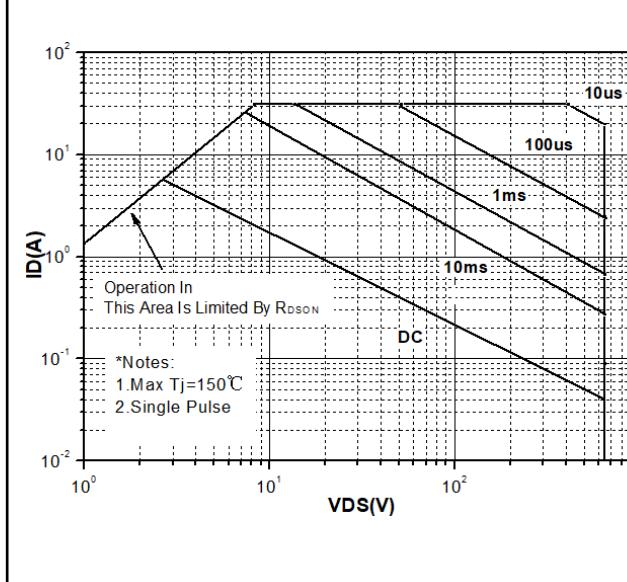
Safe operating area $T_C = 25^\circ\text{C}$ (TO220F)	Safe operating area $T_C = 80^\circ\text{C}$ (TO220F)
 <p>$I_D = f(V_{DS})$; $T_C = 25^\circ\text{C}$; $D=0$; parameter: t_P</p>	 <p>$I_D = f(V_{DS})$; $T_C = 80^\circ\text{C}$; $D=0$; parameter: t_P</p>

Table 12 Capacitances and Gate Charge

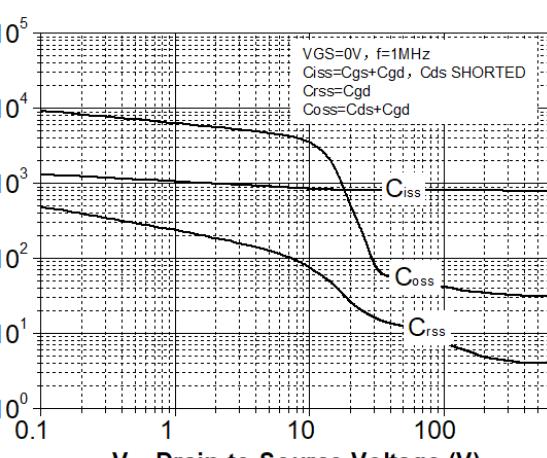
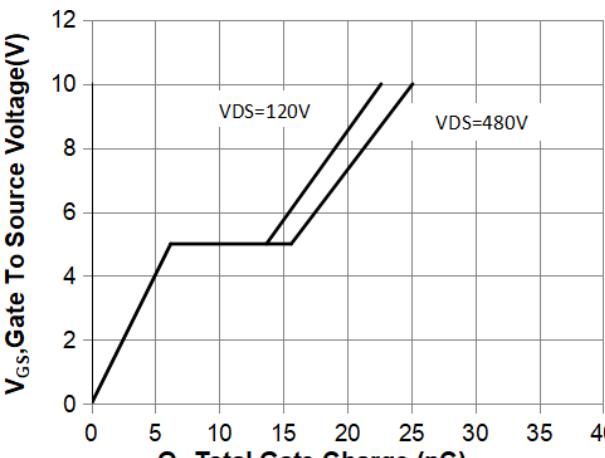
Typical Capacitances	Typical Gate charge
 <p>V_{GS}=0V, f=1MHz $C_{iss}=C_{gs}+C_{gd}$, C_{ds} SHORTED $C_{rss}=C_{gd}$ $C_{oss}=C_{ds}+C_{gd}$</p>	 <p>V_{DS}=120V V_{DS}=480V</p>
V _{gs} =0v, Freq.= 1MHz	I _D =f(Q _{gate}); I _D = 7.1A pulsed; parameter: V _{DD}

Table 13 Diode Characteristics and Avalanche Energy

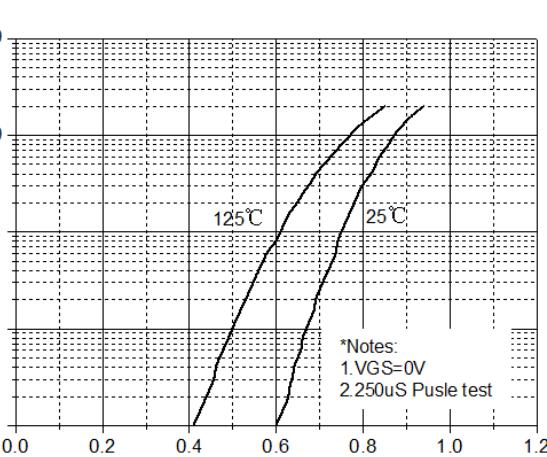
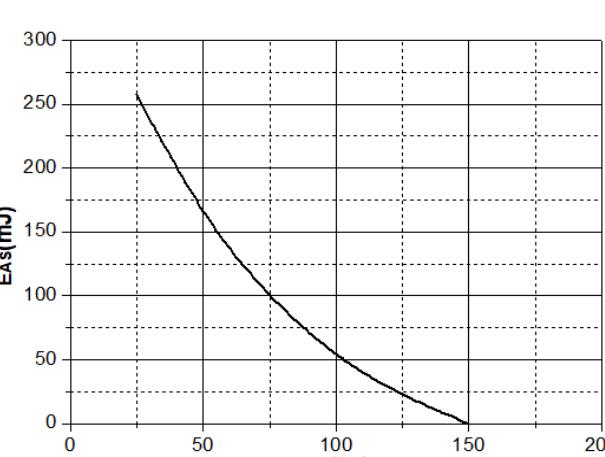
Forward characteristics of reverse diode	Avalanche energy
 <p>Notes: 1.V_{GS}=0V 2.250μS Pulse test</p>	
I _F =f(V _{SD}); parameter:T _j	E _{AS} =f(T _j); I _D = 2.4A ; V _{DD} = 50V

Table 14 Breakdown Voltage and Transfer Characteristics

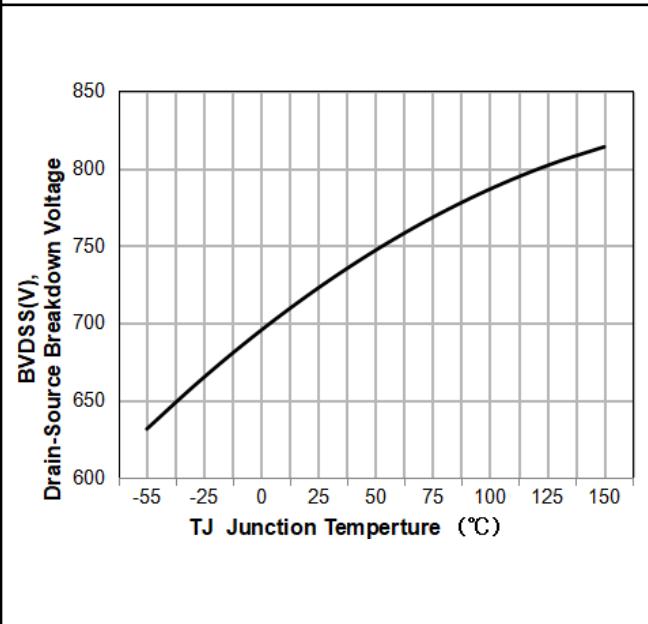
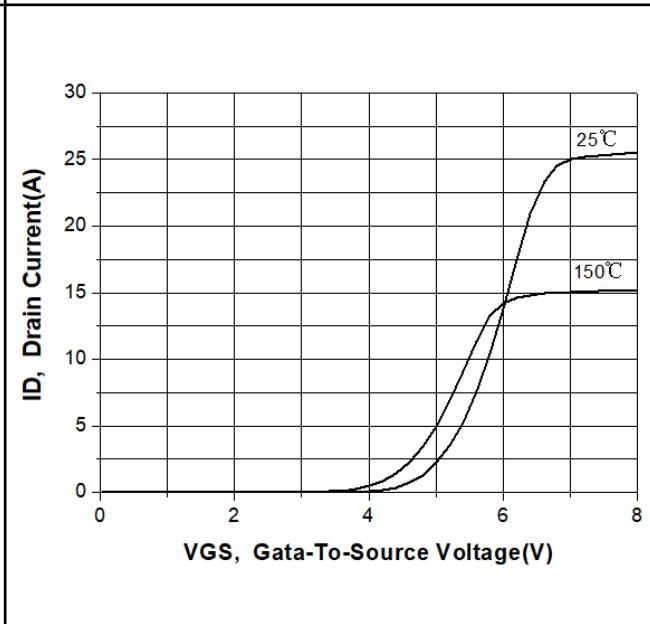
Drain-source breakdown voltage	Transfer Characteristics																																										
 <p>A line graph showing the relationship between Drain-Source Breakdown Voltage (V_{BDSS}) and Junction Temperature (T_j). The x-axis ranges from -55°C to 150°C, and the y-axis ranges from 600V to 850V. The curve starts at approximately (-55, 630) and increases monotonically, reaching about 810V at 150°C.</p> <table border="1"> <caption>Data points estimated from the graph</caption> <thead> <tr> <th>TJ Junction Temperature (°C)</th> <th>V_{BDSS} (V)</th> </tr> </thead> <tbody> <tr><td>-55</td><td>630</td></tr> <tr><td>0</td><td>680</td></tr> <tr><td>25</td><td>720</td></tr> <tr><td>50</td><td>760</td></tr> <tr><td>75</td><td>790</td></tr> <tr><td>100</td><td>810</td></tr> <tr><td>125</td><td>820</td></tr> <tr><td>150</td><td>810</td></tr> </tbody> </table>	TJ Junction Temperature (°C)	V_{BDSS} (V)	-55	630	0	680	25	720	50	760	75	790	100	810	125	820	150	810	 <p>A line graph showing the Transfer Characteristics of the FET. The x-axis is Gata-To-Source Voltage (V_{GS}) from 0V to 8V, and the y-axis is Drain Current (I_D) from 0A to 30A. Two curves are shown: one for 25°C which rises more steeply, and one for 150°C which is flatter. Both curves show a saturation region where current remains constant after a certain threshold voltage.</p> <table border="1"> <caption>Data points estimated from the graph</caption> <thead> <tr> <th>V_{GS} (V)</th> <th>I_D (A) at 25°C</th> <th>I_D (A) at 150°C</th> </tr> </thead> <tbody> <tr><td>0</td><td>0</td><td>0</td></tr> <tr><td>2</td><td>0</td><td>0</td></tr> <tr><td>4</td><td>~1</td><td>~0.5</td></tr> <tr><td>5</td><td>~10</td><td>~2</td></tr> <tr><td>6</td><td>~25</td><td>~15</td></tr> <tr><td>7</td><td>~28</td><td>~18</td></tr> <tr><td>8</td><td>~28</td><td>~18</td></tr> </tbody> </table>	V_{GS} (V)	I_D (A) at 25°C	I_D (A) at 150°C	0	0	0	2	0	0	4	~1	~0.5	5	~10	~2	6	~25	~15	7	~28	~18	8	~28	~18
TJ Junction Temperature (°C)	V_{BDSS} (V)																																										
-55	630																																										
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150	810																																										
V_{GS} (V)	I_D (A) at 25°C	I_D (A) at 150°C																																									
0	0	0																																									
2	0	0																																									
4	~1	~0.5																																									
5	~10	~2																																									
6	~25	~15																																									
7	~28	~18																																									
8	~28	~18																																									
$V_{BR(DSS)} = f(T_j)$; $I_D = 0.25\text{mA}$	$I_D = f(V_{GS})$; $ V_{DS} > 2 I_D R_{DS(On)\max}$; parameter: T_j																																										

Table 15 Diode Recovery Characteristic

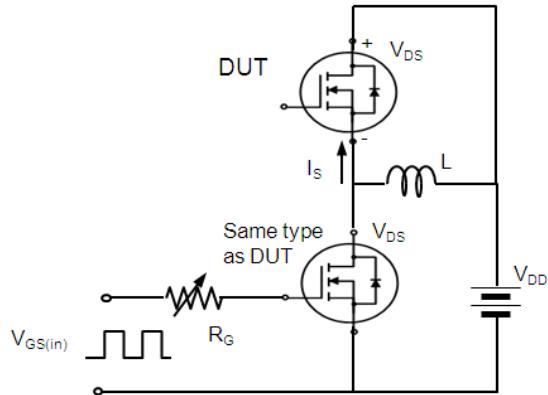
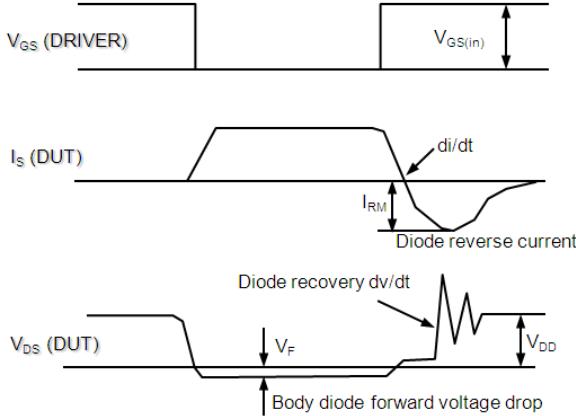
Test Circuit For Diode Recovery	Test Waveform For Diode Recovery
 <p>*. $\frac{dv}{dt}$ controlled by R_G *. I_S controlled by pulse period</p>	

Table 16 Switching Time Characteristic

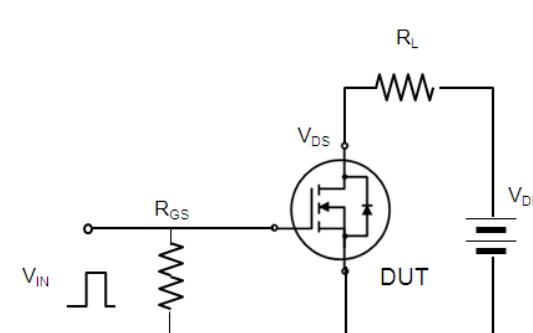
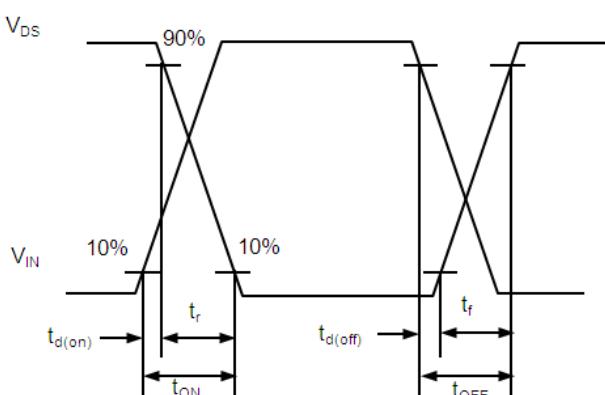
Test Circuit for Switching Time	Test Waveform for Switching Time
	

Table 17 Gate Charge Characteristic

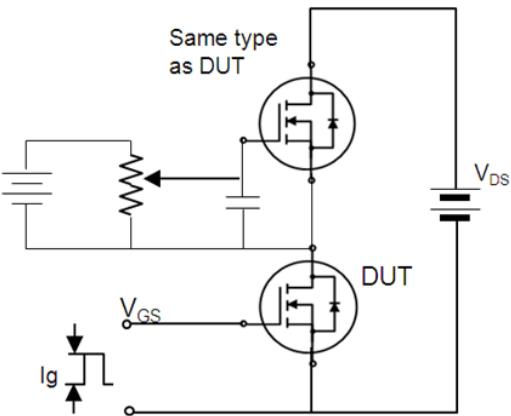
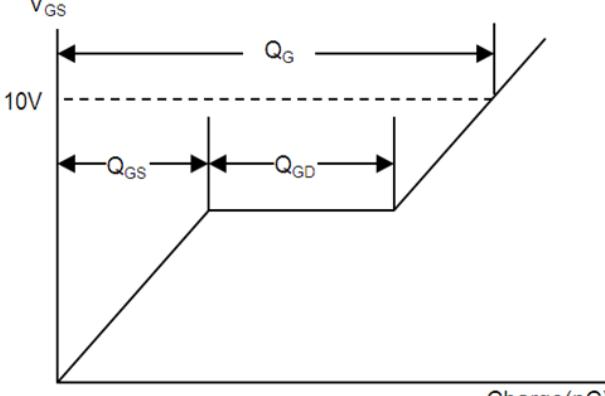
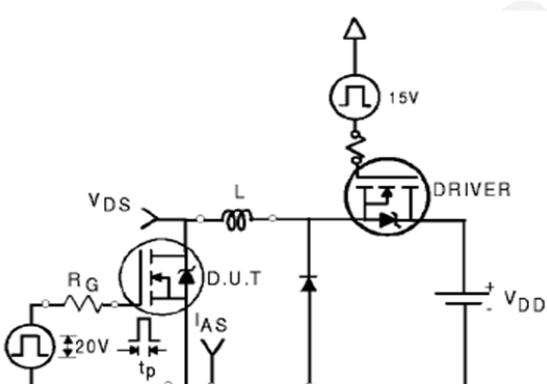
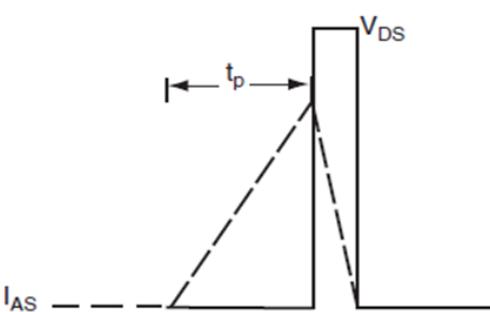
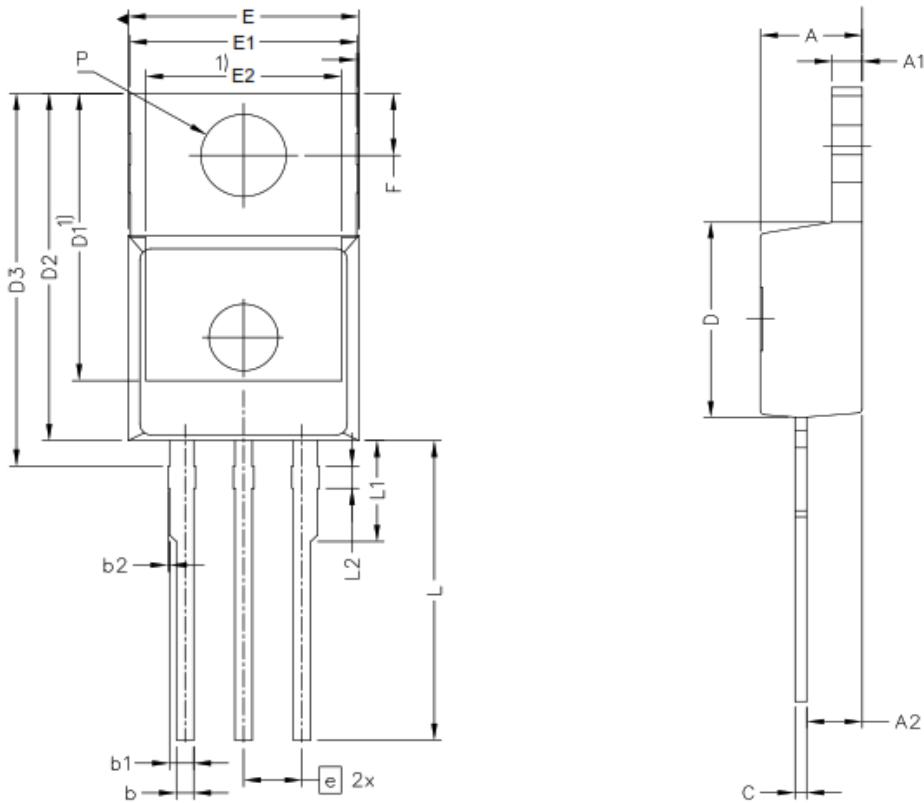
Test Circuit For Gate Charge	Test Waveform For Gate Charge
	

Table 18 Unclamped Inductive Characteristic

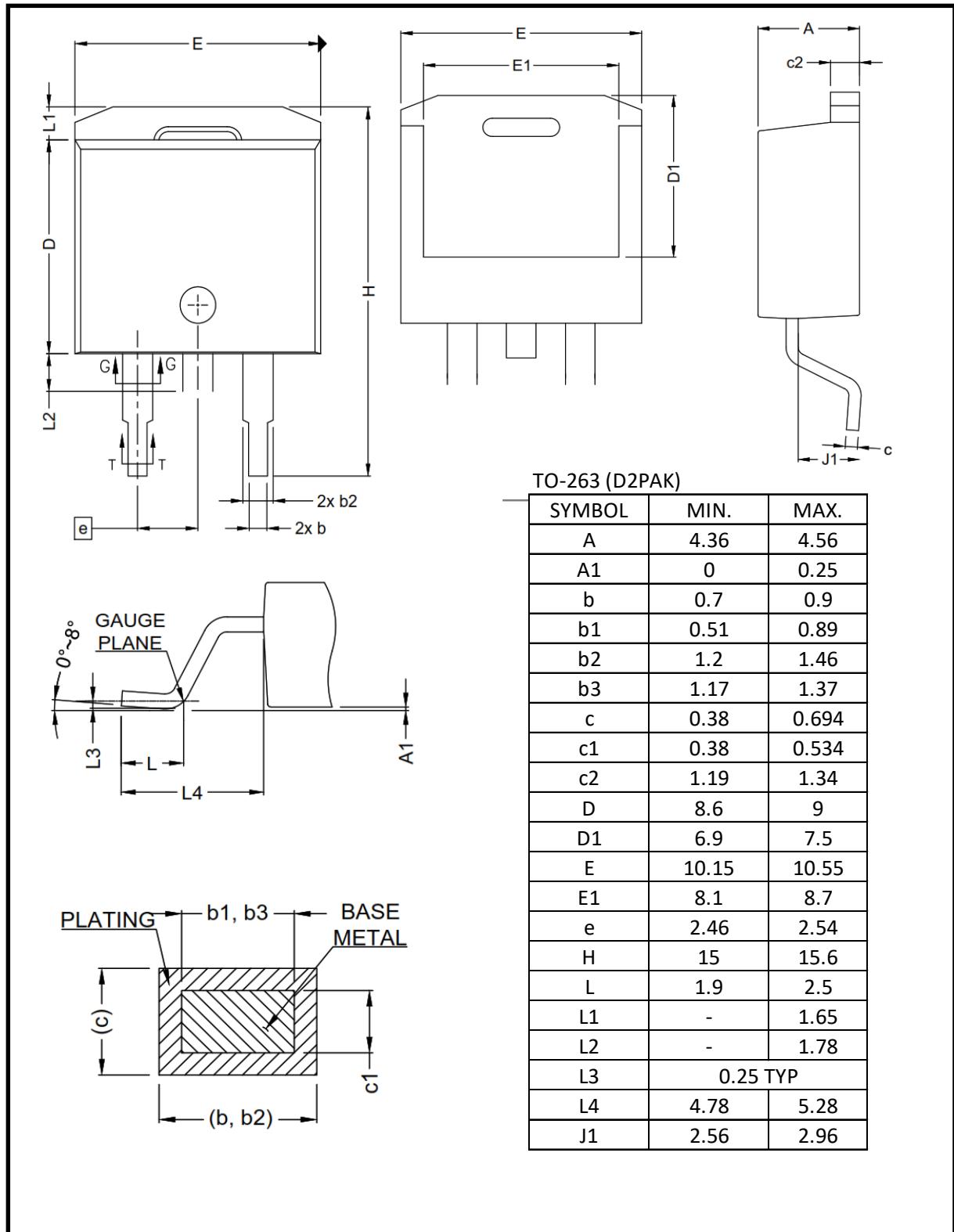
Test Circuit For Unclamped Inductive	Test Waveform For Unclamped Inductive
	$E_{AS} = \frac{1}{2} L I_{AS}^2$ 

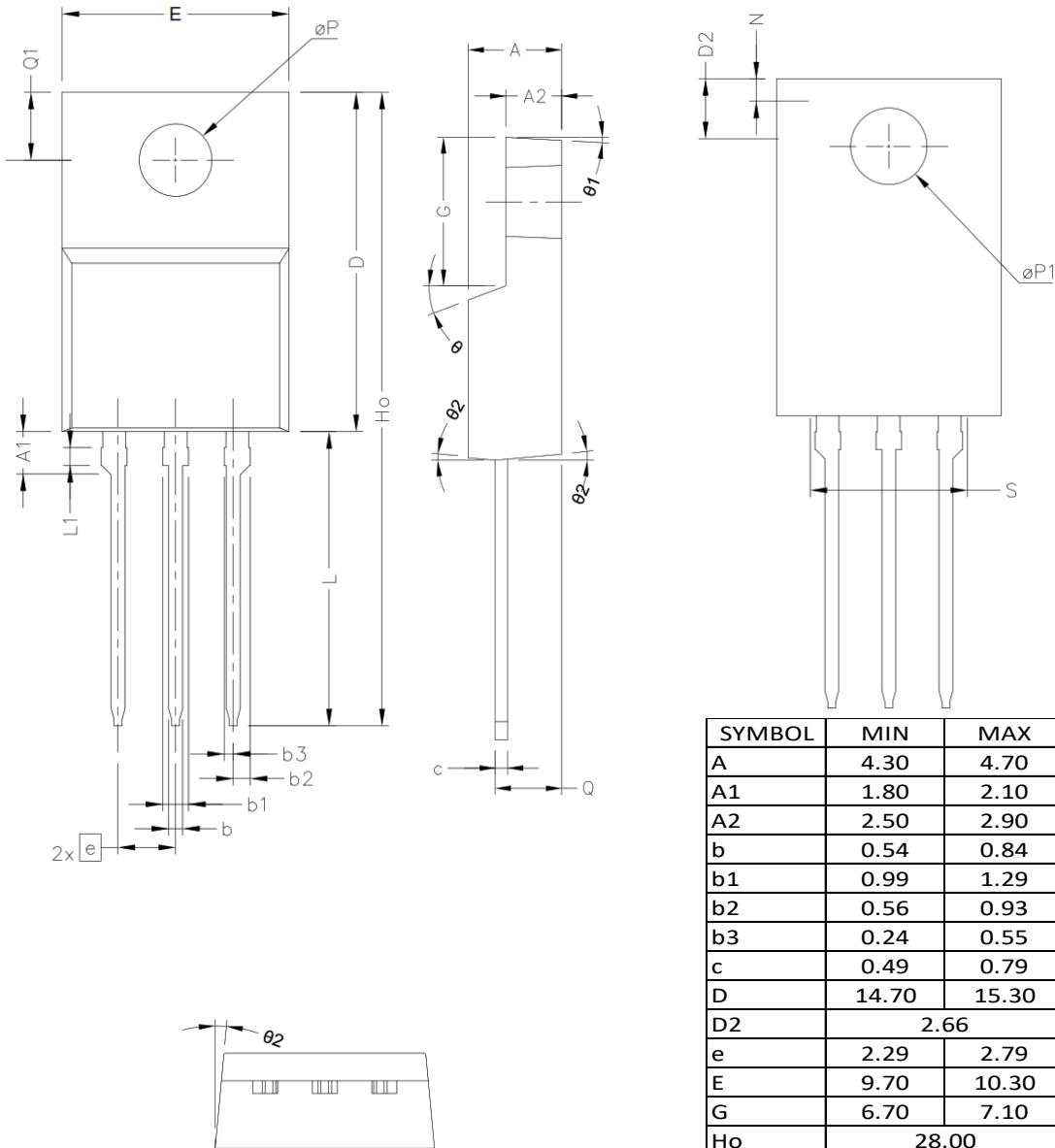
4a) TO-220



TO-220 3L

SYMBOL	MIN	MAX
A	4.20	4.60
A1	1.20	1.40
A2	2.20	2.60
b	0.65	0.85
b1	0.95	1.15
b2		0.15
C	0.40	0.60
D	9.05	9.45
D1	12.95	
D2	15.35	15.95
D3	16.50	17.10
E	9.80	10.20
E1	9.70	10.10
E2	8.50	
e	2.46	2.54
F	2.60	3.00
L	13.00	14.00
L1	4.35	4.75
L2	0.90	1.10
P	3.55	3.85

4b) TO-263


4C) TO-220 FullPak


SYMBOL	MIN	MAX
A	4.30	4.70
A1	1.80	2.10
A2	2.50	2.90
b	0.54	0.84
b1	0.99	1.29
b2	0.56	0.93
b3	0.24	0.55
c	0.49	0.79
D	14.70	15.30
D2	2.66	
e	2.29	2.79
E	9.70	10.30
G	6.70	7.10
H0	28.00	
L	12.50	13.50
L1	0.70	0.90
N		2.86
ØP	3.05	3.40
ØP1		3.40
Q	3.10	3.30
Q1	2.70	3.30
S		7.00
Ø1		3 deg.
Ø2		5 deg.

Revision History

Revision	Release Date	Comments
1.0	1-Nov 2016	Preliminary Datasheet Draft
1.5	15-June 2017	Update tables
2.0	6-Dec 2017	Update tables, characterization
2.1	11-Dec 2017	Updated Parameters
3.0	2-Jan 2019	Recharacterization and tables

Resources

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